

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/600,500	FAN, FRANK Y.H.	
		Examiner	Art Unit	Page 1 of 1
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.